13. Memories and PLAs

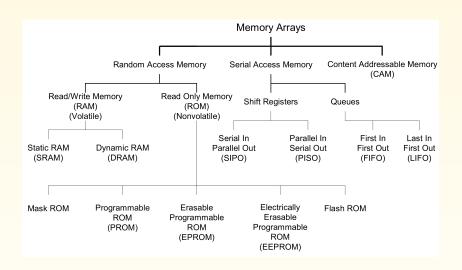
Jacob Abraham

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VLSI Design Fall 2020

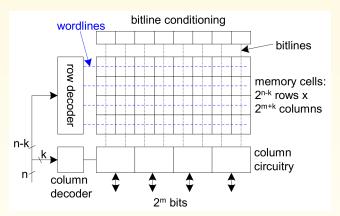
October 13, 2020

Taxonomy for Memory Arrays



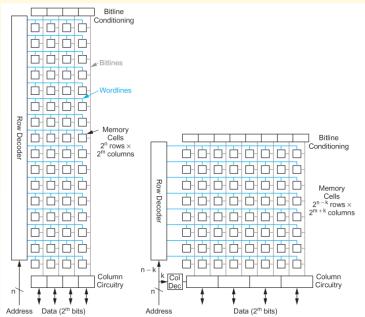
Array Architecture

- 2^n words of 2^m bits each
- If n>>m, fold by 2k into fewer rows of more columns



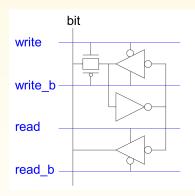
- Good regularity easy to design
- Very high density if good cells are used

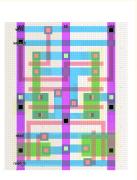
Different Memory Array Structures



12-Transistor SRAM Cell

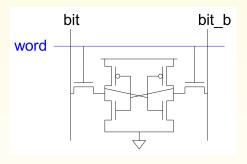
- Basic building block: SRAM Cell
 - Holds one bit of information, like a latch
 - Must be read and written
- 12-transistor (12T) SRAM cell
 - Use a simple latch connected to bitline
 - $46 \times 75 \ \lambda$ unit cell





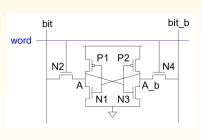
6-Transistor SRAM Cell

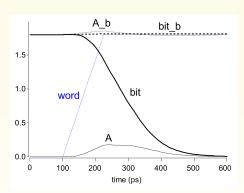
- Cell size accounts for most of array size
 - Reduce cell size at expense of complexity
- 6T SRAM Cell
 - Used in most commercial chips
 - Data stored in cross-coupled inverters
- Read:
 - Precharge bit, bit_b
 - Raise wordline
- Write
 - Drive data onto bit, bit_b
 - Raise wordline



SRAM Read

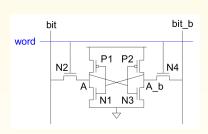
- Precharge both bitlines high
- Then turn on wordline
- One of two bitlines will be pulled down by the cell
- Example: A = 0, $A_b = 1$
 - Bit discharges, bit_b stays high
 - But A bumps up slightly
- Read stability
 - A must not flip
 - N1 >> N2

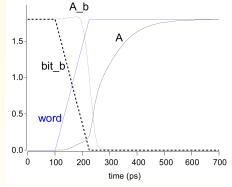




SRAM Write

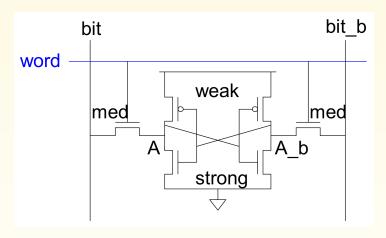
- Drive one bitline high, the other low
- Then turn on wordline
- Bitlines overpower cell with new value
- Example: A = 0, $A_b = 1$, bit = 1, bit_b = 0
 - Force A_b low, then A rises high
- Writability
 - Must overpower feedback inverter
 - N2 >> P1





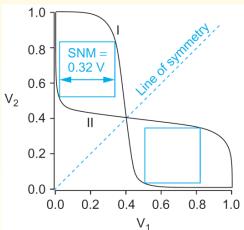
SRAM Sizing

- High bitlines must not overpower inverters during reads
- But low bitlines must write new value into cell

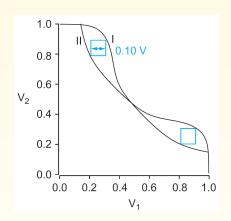


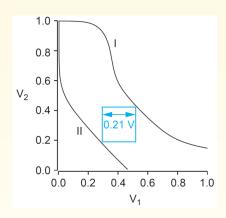
Hold Margin



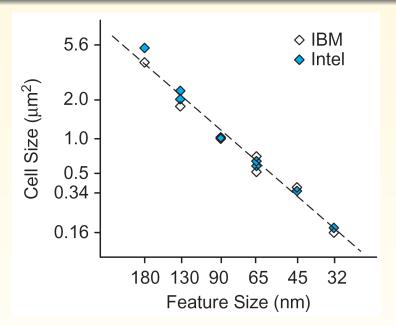


Read and Write Margins





SRAM Cell Size vs. Feature Size

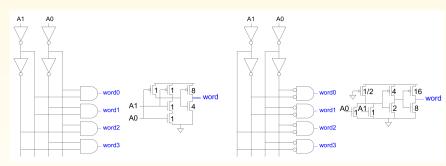


Decoders

- $n:2^n$ decoder consists of 2^n n-input AND gates
 - One needed for each row of memory
 - Build AND from NAND or NOR gates

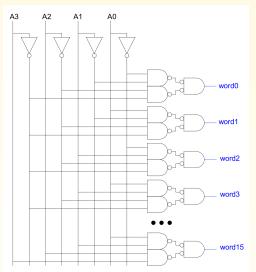
Static CMOS

Pseudo-nMOS



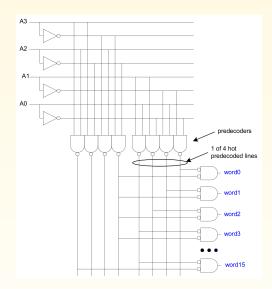
Large Decoders

- For n > 4, NAND gates become slow
 - Break large gates into multiple smaller gates



Pre-Decoding

- Many of the gates are redundant
 - Factor out common gates into predecoder
 - Saves area
 - Same path effort

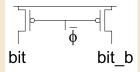


Column Circuitry

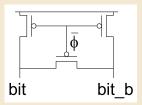
- Some circuitry is required for each column
 - Bitline conditioning
 - Sense amplifiers
 - Column multiplexing

Bitline Conditioning

 Precharge bitlines high before reads



 Equalize bitlines to minimize voltage difference when using sense amplifiers

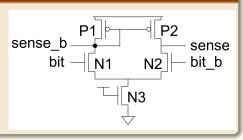


Sense Amplifiers

- Bitlines have many cells attached
 - Example, 32-kbit SRAM has 256 rows x 128 cols
 - 128 cells on each bitline
- $t_{pd} \propto (C/I)\Delta V$
 - Even with shared diffusion contacts, 64C of diffusion capacitance (big C)
 - Discharged slowly through small transistors (small I)
- ullet Sense amplifiers are triggered on a small voltage swing (reduce ΔV)

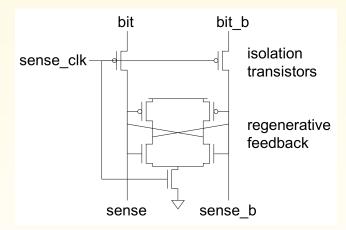
Example: Differential Pair Amplifier

- Differential pair requires no clock
- But always dissipates static power



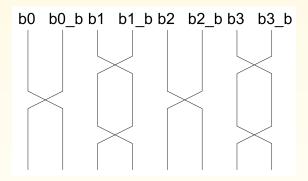
Clocked Sense Amplifier

- Clocked sense amp saves power
- Requires sense_clk after enough bitline swing
- Isolation transistors cut off large bitline capacitance



Twisted Bitlines

- Sense amplifiers also amplify noise
 - Coupling noise is severe in modern processes
 - Try to couple equally onto bit and bit_b
 - Done by twisting bitlines

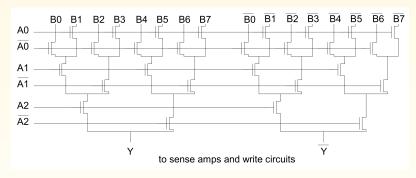


Column Multiplexing

- Recall that array may be folded for good aspect ratio
- Example: 2K word x 16 array folded into 256 rows x 128 columns
 - Must select 16 output bits from the 128 columns
 - Requires 16 8:1 column multiplexers

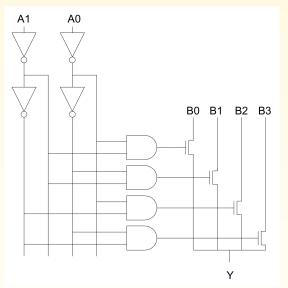
Tree Decoder Multiplexer

- Column MUX can use pass transistors
 - Use nMOS only, precharge outputs
- ullet One design is to use k series transistors for $2^k:1$ mux
 - No external decoder logic needed

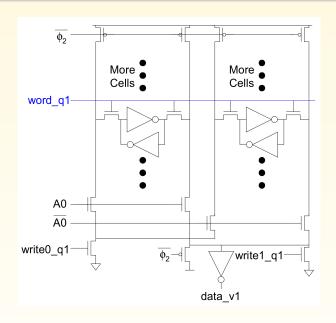


Single Pass-Gate Multiplexer

• Eliminate series transistors with separate decoder



Example: 2-Way Muxed SRAM

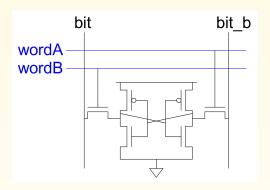


Multiple Ports

- We have considered single-ported SRAM
 - One read or one write on each cycle
- Multiported SRAMs are needed for register files
- Examples:
 - Multicycle MIPS must read two sources or write a result on some cycles
 - Pipelined MIPS must read two sources and write a third result each cycle
 - Superscalar MIPS must read and write many sources and results each cycle

Dual-Ported SRAM

- Simple dual-ported SRAM
 - Two independent single-ended reads
 - Or one differential write



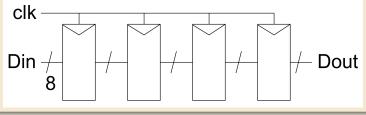
- Do two reads and one write by time multiplexing
 - Read during ph1, write during ph2

Serial Access Memories

- Serial access memories do not use an address
 - Shift Registers
 - Tapped Delay Lines
 - Serial In Parallel Out (SIPO)
 - Parallel In Serial Out (PISO)
 - Queues (FIFO, LIFO (Stacks))
- Some of these used in circuitry for communications

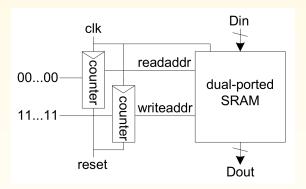
Shift Registers Store and Delay Data

- Simple design: cascade of registers
- Watch your hold times!



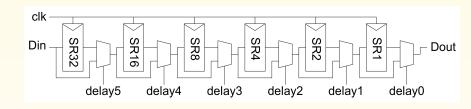
Denser Shift Registers

- Flip-flops are not very area-efficient
- For large shift registers, keep data in SRAM instead
- Move R/W pointers to RAM rather than data
 - Initialize read address to first entry, write to last
 - Increment address on each cycle



Tapped Delay Line

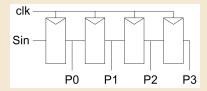
- Shifter register with a programmable number of stages
- Set number of stages with delay controls to mux
 - Example, 0 63 stages of delay



Serial/Parallel Conversion

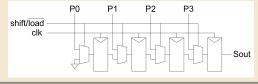
Serial In Parallel Out

- 1-bit shift register reads in serial data
 - After N steps, presents N-bit parallel output



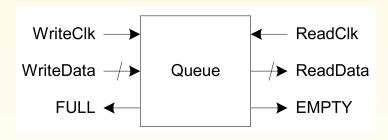
Parallel In Serial Out

- Load all N bits in parallel when shift = 0
 - Then shift one bit out per cycle



Queues

- Queues allow data to be read and written at different rates
- Read, Write each use their own clock, data
- Queue indicates whether it is full or empty
- Build with SRAM and read/write counters (pointer

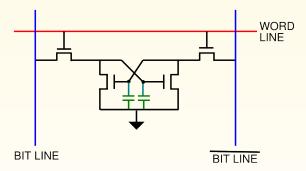


FIFO, LIFO Queues

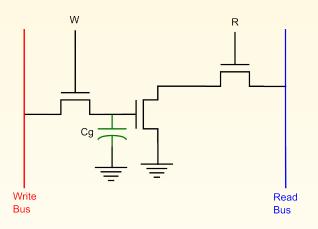
- First In First Out (FIFO)
 - Initialize read and write pointers to first element
 - Queue is EMPTY
 - On write, increment write pointer
 - If write almost catches read, Queue is FULL
 - On read, increment read pointer
- Last In First Out (FIFO)
 - Also called a stack
 - Use a single stack pointer for read and write

4-Transistor Dynamic RAM Cell

- Remove the two p-channel transistors from the static RAM cell to get a four-transistor dynamic RAM cell
- Data stored as charge on gate capacitors (complementary nodes)
- Data must be refreshed regularly
- Dynamic cells must be designed very carefully

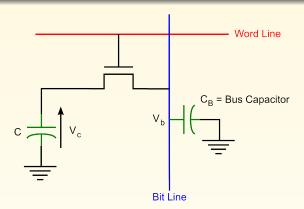


3-Transistor Dynamic RAM Cell



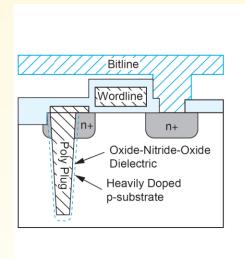
- Data stored on the gate of a transistor
- Need two additional transistors, one for write and the other for read control

1-Transistor Dynamic RAM Cell



- Cannot get any smaller than this: data stored on a (trench) capacitor C, need a transistor to control data
- Bit line normally precharged to 1/2 VDD (need a well-designed sense amplifier)
- Value of capacitances must be chosen very carefully; voltages on stored bit and bit-line affected by charge sharing

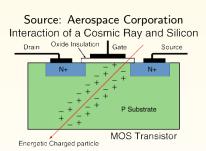
Trench Capacitor

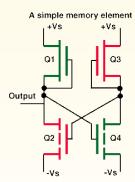




Single-Event Upsets

- High-energy particle produces electron-hole pairs in substrate; when collected at source and drain, will cause current pulse
 - Cosmic Radiation
- A "bit-flip" can occur in the memory cell due to the charge generated by the particle – called a "single-event upset"
- Seen in spacecraft electronics in the past, now in computers on the ground





Embedded Memory IP (Intellectual Property)

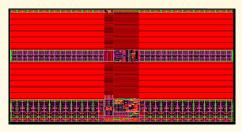
Example, from ARM

- Single Port SRAM
- Dual Port SRAM
- Single Port Register file
- Two Port Register file
- Via and Diffusion Programmable ROM

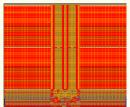
Memory Compilers

- Automatically generate memory structures
- High density, high speed and low power SRAMs
- Over 15 different foundries and 65 process variants from 28nm to 250nm

ARM Embedded Memory IP



SRAM IP

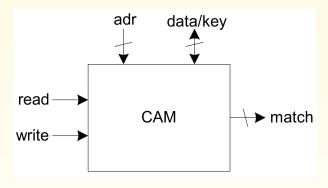


Register File IP

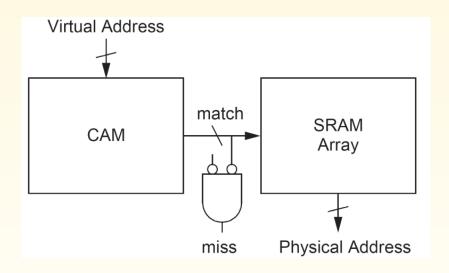
Source: ARM (http://www.arm.com/products/physical-ip/
embedded-memory-ip/index.php)

Content Addressable Memories (CAMs)

- Extension of ordinary memory (e.g., SRAM)
 - Read and write memory as usual
 - Also match to see which words contain a key

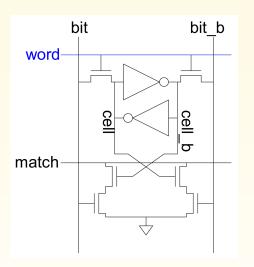


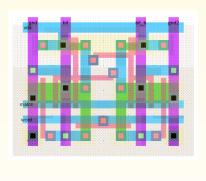
Translation Lookaside Buffer (TLB) Using CAM



10-Transistor CAM Cell

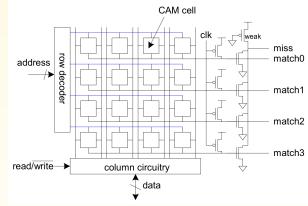
- Add four match transistors to 6T SRAM
 - $56 \times 43 \ \lambda$ unit cell





CAM Cell Operation

- Read and write like ordinary SRAM
- Additional "match" operation
- For matching:
 - Leave wordline low
 - Precharge matchlines
 - Place key on bitlines
 - Matchlines evaluate
- Miss line
 - Pseudo-nMOS NOR of match lines
 - Goes high if no words match



Read-Only Memories (ROMs)

- Read-Only Memories are nonvolatile
 - Retain their contents when power is removed
- Mask-programmed ROMs use one transistor per bit
 - Presence or absence determines 1 or 0

Example: 4-word \times 6-bit ROM

A1 A0 pseudo-nMOS pullups

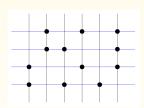
2:4
DEC
ROM Array

Looks like 6 4-input pseudo-nMOS NORs

Can be represented by a "dot diagram"

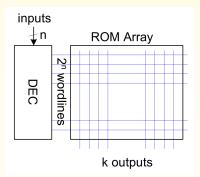
Dots indicate 1s in ROM

Word 0: 010101 Word 1: 011001 Word 2: 100101 Word 3: 101010

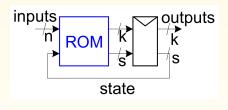


Building Logic with ROMs

- ROM as lookup table containing truth table
 - n inputs, k outputs requires 2^n words $\times k$ bits
 - Changing function is easy - reprogram ROM

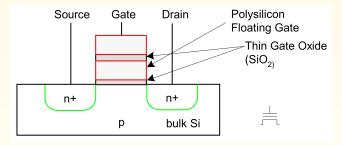


- Finite State Machine
 - n inputs, k outputs, s bits of state
 - Build with $2^{n+s} \times (k+s)$ bit ROM and (k+s) bit register

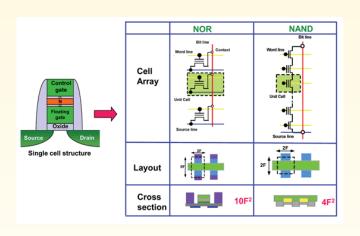


PROMs and EPROMs

- Programmable ROMs (PROMs)
 - Build array with transistors at every site
 - Burn out fuses to disable unwanted transistors
- Electrically Programmable ROMs (EPROMs)
 - Use floating gate to turn off unwanted transistors
 - EPROM, EEPROM, Flash

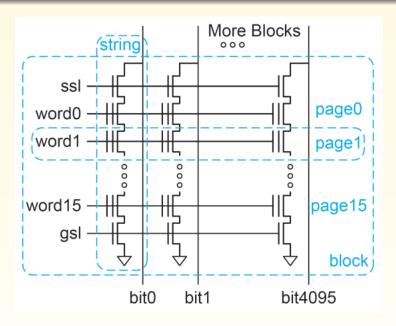


Flash Memory



Source: www.ctimes.com.tw

NAND Flash String



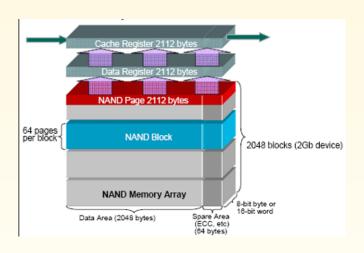
Erase and Program Operations

| 0 V | 20 V | 20 V | 20 V | 10 V |
|---------|---------|--------------|-----------|---------|
| <u></u> | <u></u> | <u></u> | <u></u> | <u></u> |
| 二 | 二 | 0 V <u> </u> | 8 V 🖳 8 V | ?ू ? |
| 20 V | 20 V | 0 V | 0 V | 0 V |
| | Inhibit | | Do Not | Inhibit |
| Erase | Erase | Program 0 | Program | Program |

Issues: Retention Time, Endurance

"Wear leveling" to increase endurance

Flash Memory Architecture



Source: EE Times

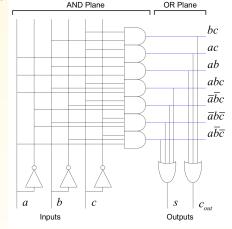
Programmable Logic Arrays (PLAs)

A Programmable Logic Array performs any function in sum-of-products form

- Literals: inputs and complements
- Products terms: AND of literals
- Outputs: OR of Product terms

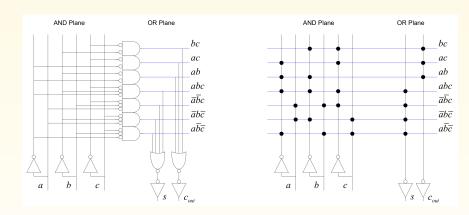
Example: Full Adder $s = ab\bar{c} + \bar{a}b\bar{c} + \bar{a}bc + abc$

$$s = ab\bar{c} + \bar{a}b\bar{c} + \bar{a}bc + abc$$
$$c = ab + bc + ac$$

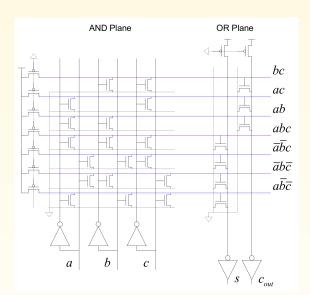


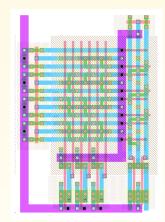
NOR-NOR PLAs

- ANDs and ORs not very efficient in CMOS
- Dynamic or Pseudo-nMOS NORs very efficient
- Use DeMorgan's Law to convert to all NORs

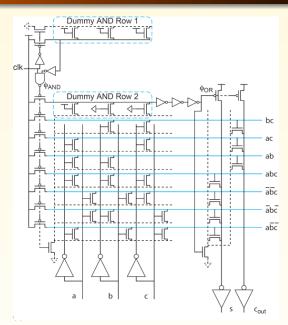


PLA Schematic and Layout





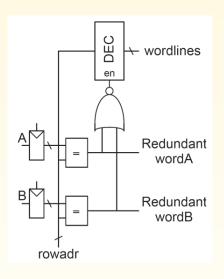
Dynamic PLA



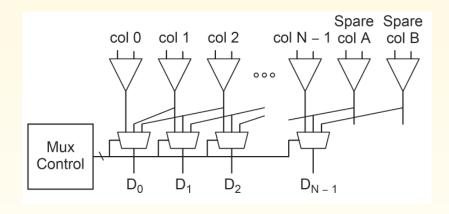
PLAs versus ROMs

- The OR plane of the PLA is like the ROM array
- The AND plane of the PLA is like the ROM decoder
- PLAs are more flexible than ROMs.
 - No need to have 2^n rows for n inputs
 - Only generate the product terms that are needed
 - Take advantage of logic simplification

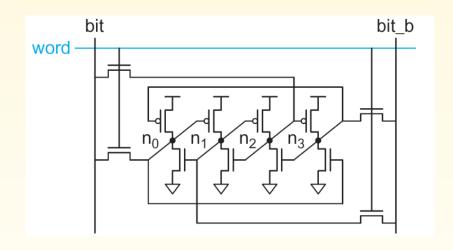
Row Redundancy to Tolerate Failures



Column Redundancy to Tolerate Failures



Radiation-Hardened SRAM Cell

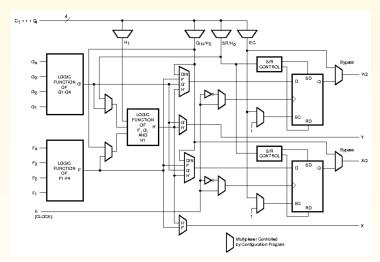


Alternative Solution: Use Error Correcting Codes

Field Programmable Logic Arrays (FPGAs)

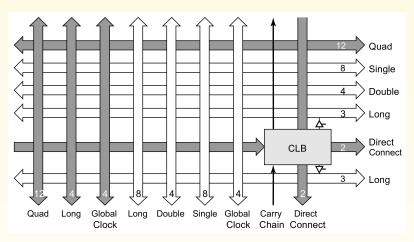
Lookup Table based logic cell

Xilinx 4000 Series

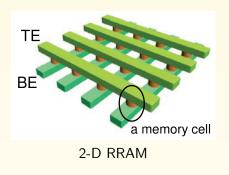


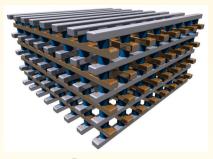
Xilinx 4000 Interconnect Architecture

Source: Xilinx



Resistive RAM (RRAM)





3-D cross-point

Source: Crossbar, Inc.